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scanning electron microscopy (SEM)

Any analytical technique which involves the generation and evaluation of secondary electrons (and to a lesser extent back scattered electrons) by a finely focused electron beam (typically 10 nm or less) for high resolution and high depth of field imaging.

Source:
PAC, 1983, *55*, 2023 *(Nomenclature, symbols and units recommended for in situ microanalysis (Provisional))* on page 2024

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